|   | ATTY. DOCKET NO.<br>2345/108        | SERIAL NO.<br>09/462,283  |
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| INFORMATION DISCLOSURE STATEMENT BY APPLICANT | APPLICANT Hans Wilfried Peter KOOPS |                           |
|   | FILING DATE Jan. 5, 2000            | GROUP 1746 To be assigned |

## U. S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL | PATENT<br>NUMBER | PATENT<br>DATE | NAME | CLASS | SUBCLASS | FILING<br>DATE |  |
|---------------------|------------------|----------------|------|-------|----------|----------------|--|
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## FOREIGN PATENT DOCUMENTS

|                     |                    | T                               |         |       |                   | TRANSLATION |    |
|---------------------|--------------------|---------------------------------|---------|-------|-------------------|-------------|----|
| EXAMINER<br>INITIAL | DOCUMENT<br>NUMBER | DATE                            | COUNTRY | CLASS | SUBCLASS          | YES         | NO |
| HATTILE             | 196 16 324*        | October 30, 1997                | Germany |       |                   |             | -  |
|                     | 0 614 126*         | September 7, 1994               | Europe  |       |                   |             | ├  |
|                     | 63 249837*         | October 17, 1988                | Japan_  |       |                   |             | +- |
| SA                  | 24 46 789**        | September 2, 1976               | Germany |       |                   | <br>        | ┼╌ |
|                     | 24 60 716**        | May 6, 1976                     | Germany |       |                   |             | ╁  |
|                     | 24 60 715**        | June 24, 1976                   | Germany |       |                   |             | ╀  |
|                     | 25 15 550**        | October 7, 1976                 | Germany |       |                   |             | +  |
|                     |                    | is cited in Search Report (copy |         |       | Sparching Authori |             | Ь_ |

<sup>\*</sup>Copy of Reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

\*\* Mentioned in the Specification.

## OTHER DOCUMENTS

| OTHER DOCUMENTS     |   |  |  |  |
|---------------------|---|--|--|--|
| EXAMINER<br>INITIAL | AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.  |  |  |  |
| SA                  | Kashyap, "Photosensitive Optical Fibers: Devices and Applications," Opt. Fibres Techn. 1, pp. 17-314 (1994).  |  |  |  |
|                     | Cremer et al., "Bragg Gratings on InGaAsP/InP-Waveguides as Polarization Independent Optical Filters," J. of Lightwave Techn., 7,11, 1641 (1989).   |  |  |  |
|                     | Alferness et al, "Broadly tunable InGaAsP/InP buried rib waveguide vertical coupler filter," Appl. Phys. Lett., 60, 8, 980 (1992).  |  |  |  |
|                     | Wu et al., "InGaAst/Inp Vertical Filter with Optimally Designed Wavelength Tunability," IEEE Photonics Technol. Lett.,  |  |  |  |
|                     | Chuang et al., "Enhanced wavelength tuning in grating assisted codirectional coupler filter," IEEE Photonics Technology   |  |  |  |
|                     | Losch et al., "Optical Waveguide Materials," (M.M. Broer, G.H. Sigel, Jr., R. Th. Kersten, H. Kawazoe ed) Mat. Res. Soc. 244, Pittsburg, PA 1992, pp. 253-262.                                  |  |  |  |
|                     | Ebeling, "Integrierte Optoelektronik," (Springer Verlag 1989) 81; pp. 78-88.  |  |  |  |
|                     | Kerber et al., "Surface imaging with HMCTS on SAL resists, a dry developable electron beam process with high sensititivity and good resolution," Microelectronic Engineering 21 (1993) 275-278. |  |  |  |
| <b>1</b>            | Koops et al., "Endpoint detection for silylation processes with waveguide modes," Microelectronic Engineering 21 (1993) 235-238, and in source 10, by J. Vac, SCI Technol. B6(1) (1988) 477.    |  |  |  |

| EXAMINER<br>INITIAL | AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.   |
|---------------------|--|
| 5A                  | Kallweit et al., "Ion Beam Induced Changes of the Refractive Index of PMMA," Radiation Effects and Defects in Solids, 1991, vol. 116, pp. 29-36, and in source 12 by Kallweit et al.                                   |
|                     | Kallweit et al., "Long-Term Studies on the Optical Performance of Ion Implanted PMMA Under the Influence of Different Media," Mat. Res. Soc. Symp. Proc. Vol. 338 (1994) 619-624.                                      |
|                     | Eich et al., "Second harmonic generation in poled organic monomeric glasses," J. Opt. Soc. Am B, 6, 8, (1989).   |
|                     | Eich et al., "Corona Poling and Real Time Second Harmonic Generation Study of a Novel Covalently Functionalized Amorphous Nonlinear Optical Polymer," J. Appl. Phys., 66, 6, (1989) R. Birenheide.                     |
|                     | Eich et al., "Analysis of Reorientational Processes in Liquid Crystalline Side Chain Polymers Using Dielectric Relaxation, Electro-Optical Relaxation and Switching Studies," Mol. Cryst. Liq. Cryst., 177, 13 (1989). |
|                     | Eich et al., "Poled Amorphous Polymers of Second Order Nonlinear Optics," Polymers for Advanced Technologies, 1, 189 (1990).   |
|                     | Stadler et al., "Electrically switchable diffractive optical element for image processing," Optics Letters 19, 1 (1994).   |
|                     | Koops et al., "High Resolution Electron Beam Induced Deposition," Proc. 3 1. Int. Symp. On Electron, Ion, and Photon Beams, J. Vac. Sci. Technol. B 6 (1) (1988) 477.  |
|                     | Koops et al., "Constructive 3-dimensional Lithography with Electron Beam Induced Deposition for Quantum Effect Devices," J. Vac. Sci. Technol. B 10(6) Nov., Dec. (1993) 2386-2389.                                    |
|                     | Koops et al., "Characterization and application of materials grown by electron beam induced deposition," Invited lecture Micro Process 1994, Jpn. J. Appl. Vol. 33 (1994) 7099-7107, part 1 no. 12B, Dec. 1994.        |
|                     | Koops, "Capacities of Electron Beam Reducing Image Projection Systems having Dynamically Compensated Field Aberrations," Microelectronic Engineering 9 (1989) 217-220.   |
|                     | Elsner et al., "Multiple Bearn-shaping Diaphragm for Efficient Exposure of Gratings," J. Vac. Sci. Technol. B 0(6) Nov., Dec. (1993) 2373-2376.  |
|                     | Elsner et al., "Advanced Multiple Beam-shaping Diaphragm for Efficient Exposure," Microelectronic Engineering 23 (1994) 85-88.   |
| SA                  | Rüb et al., "Electron-beam-induced deposition in a reducing image projector," Microelectronic Engineering 9 (1989) 251-  |

| EXAMINER    | Shanim Ahmed | DATE CONSIDERED | 7/24/01 |
|-------------|--------------|-----------------|---------|
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